

FORM PTO 1449 (modified)

ATTY DOCKET NO.

35.C10499 CI/DI

APPLICATION NO.

To be assigned

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

APPLICANTS

HIDEAKI MITSUTAKE, ET AL.

LIST OF REFERENCES CITED BY APPLICANT(S)  
(Use several sheets if necessary)

FILING DATE

March 23, 1998

GROUP  
2215

Date Submitted to PTO: March 23, 1998

JC587 U.S. \$ 04/5681  
03/23/98

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
w		4,904,895	02/1990	Tsukamoto, et al.	313	336	
w		5,066,883	11/1991	Yoshioka, et al.	313	309	
w		4,451,759	05/1984	Heynisch	313	495	
w		4,954,744	09/1990	Suzuki, et al.	313	355X	

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
w		2-257551	10/1990	Japan			Abstract
w		4-28137	01/1992	Japan			Abstract
w		3-55738	03/1991	Japan			Abstract

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

w	H. C. Miller, "Improving the Voltage Holdoff Performance of Alumina Insulators in Vacuum Through Quasimentallizing", IEEE Transactions on Electrical Insulation, Vol. EI-15, No. 5, pp. 419-428 (October 1980).
w	H.C. Miller, "Improving the Voltage Holdoff Performance of Alumina Insulator Vacuum by Quasimentallizing or Doping", Physica 104C, pp. 183-188 (1981).
w	H.C. Miller, et al., "The Effect of Mn/Ti Surface Treatment on Voltage-Holdoff Performance of Alumina Insulators in Vacuum", J.Appl. Phys., Vol. 49, No. 11, pp. 5416-5420 (November 1978).
w	T. Sudarshan, et al., "The Effect of Chromium Oxide Coatings on Surface Flashover of Alumina Spacers in Vacuum", IEEE Transactions on Electrical Insulation, Vol. EI-11, No. 1, pp. 32-35 (March 1976).
w	C.A. Mead, "Operation of Tunnel-Emission Devices", Journal of Applied Physics, vol. 32, No. 4, pp. 646-652 (April 1961)
w	C.A. Spindt, et al., "Physical Properties of Thin-Film Field Emission Cathodes with Molybdenum Cones", Journal of Applied Physics, Vol. 47, No. 12, pp. 5248-5263 (December 1976).
w	M.I. Elinson, et al., "The Emission of Hot Electrons and the Field Emission of Electrons From Tin Oxide", Radio Engineering and Electronic Physics, No. 7, pp. 1290-1296 (July 1965).

EXAMINER *Matthew Shin*

DATE CONSIDERED

10-21-98

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## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>w</i>		5,371,433	12/1994	Horne, et al.	313	292X	
<i>w</i>		5,532,548	07/1996	Spindt, et al.	313	292X	

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<i>w</i>		64-31332	02/1989	Japan			Abstract
<i>w</i>		WO 94/18694	08/1994	PCT			
<i>w</i>		0 405 262	01/1991	Europe			
<i>w</i>		0 523 702	01/1993	Europe			
<i>w</i>		0 048 839	04/1982	Europe			No
<i>w</i>		0 580 244	01/1994	Europe			
<i>w</i>		57-118355	07/1982	Japan			Yes

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>Look to consider</i>	R. Meyer, et al., "Recent Development on "Microtips" Display at LETI", Technical Digest of IVMC 91, pp. 6-9, Nagahara (1991). <i>O.K.</i>
	G. Dittmer, "Electrical Conduction and Electron Emission of Discontinuous Thin Films", Thin Solid Films, Vol. 9, pp. 317-328 (1972). <i>O.K.</i>
	H. Araki, et al., "Electroforming and Electron Emission of Carbon Thin Films", Journal of the Vacuum Society of Japan, Vol. 26, No. 1, pp. 22-29 (January 26, 1983).
	M. Hartwell, et al., "Strong Electron Emission From Patterned Tin-Indium Oxide Thin Films", International Electron Devices Meeting, pp. 519-521 (1975). <i>O.K.</i>
	<del>W.P. Dyke, et al., "Field Emission", Advances in Electronics and Electron Physics, Vol. VIII (1956).</del>

EXAMINER *[Signature]*

DATE CONSIDERED

10-21-98

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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.